

INTERNATIONAL SEARCH REPORT

International Application No
PCT/AT 03/00018

A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01R31/308 G01R31/311 G01R31/302 G01N21/17		
According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) IPC 7 G01R G01N		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practical, search terms used) INSPEC, EPO-Internal		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	DONALDSON W R ET AL: "Integrated circuit tester using interferometric imaging" PROCEEDINGS OF THE UGIM SYMPOSIUM, MICROELECTRONICS EDUCATION FOR THE FUTURE. TWELFTH BIENNIAL UNIVERSITY/GOVERNMENT/INDUSTRY MICROELECTRONICS SYMPOSIUM (CAT. NO.97CH36030), PROCEEDINGS OF THE UGIM SYMPOSIUM, MICROELECTRONICS EDUCATION FOR THE FUTURE, page 107 XP010242546 1997, New York, NY, USA, IEEE, USA ISBN: 0-7803-3790-5 figure 1 --- -/-	1-33
<input checked="" type="checkbox"/> Further documents are listed in the continuation of box C.		
<input checked="" type="checkbox"/> Patent family members are listed in annex.		
* Special categories of cited documents:		
A document defining the general state of the art which is not considered to be of particular relevance *E* earlier document but published on or after the international filing date *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) *O* document referring to an oral disclosure, use, exhibition or other means *P* document published prior to the international filing date but later than the priority date claimed *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art *&* document member of the same patent family		
Date of the actual completion of the international search 2 May 2003		Date of mailing of the international search report 19/05/2003
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016		Authorized officer Mason, W

INTERNATIONAL SEARCH REPORT

International Application No

PCT/AT 03/00018

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	CARTWRIGHT A N ET AL: "Femtosecond interferometry for analysis of internal bond interface delamination in semiconductor devices" TECHNICAL DIGEST. SUMMARIES OF PAPERS PRESENTED AT THE CONFERENCE ON LASERS AND ELECTRO-OPTICS. CONFERENCE EDITION. 1998 TECHNICAL DIGEST SERIES, VOL.6 (IEEE CAT. NO.98CH36178), TECHNICAL DIGEST SUMMARIES OF PAPERS PRESENTED AT THE CONFERENCE ON LASE, pages 356-357, XP002239978 1998, Washington, DC, USA, Opt. Soc. America, USA ISBN: 1-55752-339-0 figures 1-3	1-33
X	DE 100 47 136 A (SCHLUMBERGER TECHNOLOGIES INC) 19 April 2001 (2001-04-19) figure 1	1-33
A	WO 00 57159 A (BOXER CROSS INC) 28 September 2000 (2000-09-28) figures 1A,,5	1-33
A	DE 198 40 725 A (FBH FERDINAND BRAUN INST FUER ;GF MESTECHNIK GMBH (DE)) 18 March 1999 (1999-03-18) figures 1,2	1-33
A	"INTERFEROMETRIC MONITOR OF SUBSTRATE HEATING INDUCED BY PULSED LASER IRRADIATION" IBM TECHNICAL DISCLOSURE BULLETIN, IBM CORP. NEW YORK, US, vol. 31, no. 8, 1989, pages 214-219, XP000036937 ISSN: 0018-8689 figure 1	1-33
A	DE 195 16 842 A (FRAUNHOFER GES FORSCHUNG) 30 November 1995 (1995-11-30) figure 1	1-33
A	YIFAN GUO ET AL: "A practical die stress model and its applications in flip-chip packages" CONFERENCE PROCEEDINGS ARTICLE, vol. 1, 23 May 2000 (2000-05-23), pages 393-399, XP010510427 page 395; figure 3	1-33
A	US 5 414 513 A (LEIB KENNETH G) 9 May 1995 (1995-05-09) figure 1	1-33
	-/-	

INTERNATIONAL SEARCH REPORT

International Application No

PCT/AT 03/00018

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 4 957 367 A (DULMAN LEV) 18 September 1990 (1990-09-18) figure 2	1-33
A	NASSIM K ET AL: "High-resolution interferometry and electronic speckle pattern interferometry applied to the thermomechanical study of a MOS power transistor" MICROELECTRONICS JOURNAL, MACKINTOSH PUBLICATIONS LTD. LUTON, GB, vol. 30, no. 11, November 1999 (1999-11), pages 1125-1128, XP004175865 ISSN: 0026-2692 figure 1	1-33

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No.

PCT/AT 03/00018

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
DE 10047136	A	19-04-2001	US 6496261 B1	17-12-2002
			DE 10047136 A1	19-04-2001
			JP 2001159665 A	12-06-2001
WO 0057159	A	28-09-2000	US 6323951 B1	27-11-2001
			AU 3530000 A	09-10-2000
			EP 1192444 A1	03-04-2002
			JP 2002540396 T	26-11-2002
			WO 0057159 A1	28-09-2000
			US 2003043382 A1	06-03-2003
			US 2002027660 A1	07-03-2002
			US 2002085211 A1	04-07-2002
DE 19840725	A	18-03-1999	DE 29715904 U1	23-10-1997
			DE 19840725 A1	18-03-1999
DE 19516842	A	30-11-1995	DE 19516842 A1	30-11-1995
US 5414513	A	09-05-1995	NONE	
US 4957367	A	18-09-1990	EP 0419517 A1	03-04-1991
			JP 4504015 T	16-07-1992
			WO 8912224 A1	14-12-1989